

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/613,922	UTTERBERG, DAVID S.	
Examiner Mark K Han		Art Unit 3763	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
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